

Search Notes

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10/725,309

Examiner

Quynh H. Nguyen

Applicant(s)/Patent under
Reexamination

CHANG ET AL.

Art Unit

2614

SEARCHED

Class	Subclass	Date	Examiner
379	220.01 387.01 201.01 93.01	3/27/2007	

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East search includes search in USPat,USPub,Derwen,JPO, and EPO databases	3/27/2007	QN
Inventor name search via PALM database	3/27/2007	QN